



X-RAY PHOTOELECTRON SPECTROSCOPY (XPS)

MANUFACTURER : Kratos Analytical

MODEL : Axis-Ultra

Analysis

- Multifunction apparatus equipped with an ultra-high vacuum system
- Bi-dimensional characterization of heterogeneous surfaces via energy-resolved parallel XPS imaging
- Surface analysis coupling 3 characterization techniques: X-ray Photoelectron Spectroscopy (XPS); Ion Scattering Spectroscopy (ISS); Auger Scanning Microscopy (ASM)

Characteristics

- Double Source Mg-Al
- Monochromatic Al Source Al
- Large radius hemispherical analyzer
- 8 channel detection
- Resolution is 0.48 eV on Silver
- Integrated high temperature and high pressure reactor

MODES

ISS

- Model : ISS Kratos-Ultra
- Resolution : 1.2% with He 1000 eV (Au)

ASM

- Model : AES Kratos-Ultra
- Canon 10 keV LAB6
- Spatial resolution : 0.1 μm
- S/N : from 500 to 500 kcps on Cu-KLL